

S1: (arrow marks) HRs>99.9%@1064 nm + HTp>98%@1064 nm (Tp/Ts >10001), AOI=45 deg +/-1 deg  
S2: ARp<0.1%@1064 nm, AOI=45 deg

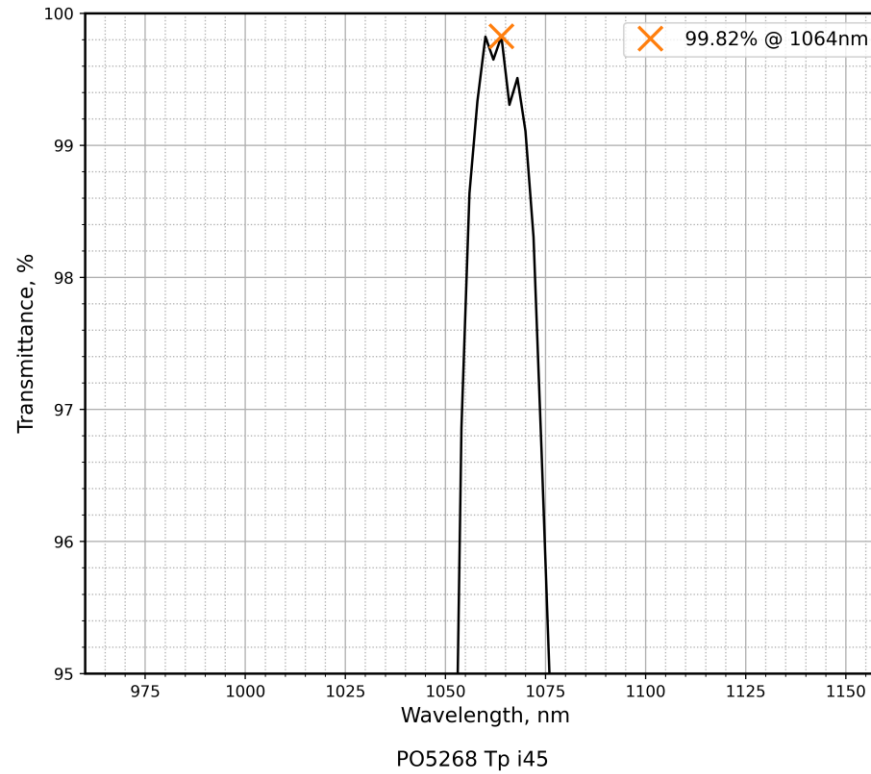


Fig. 1.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRs>99.9%@1064 nm + HTP>98%@1064 nm (Tp/Ts >10001), AOI=45 deg +/-1 deg  
S2: ARp<0.1%@1064 nm, AOI=45 deg

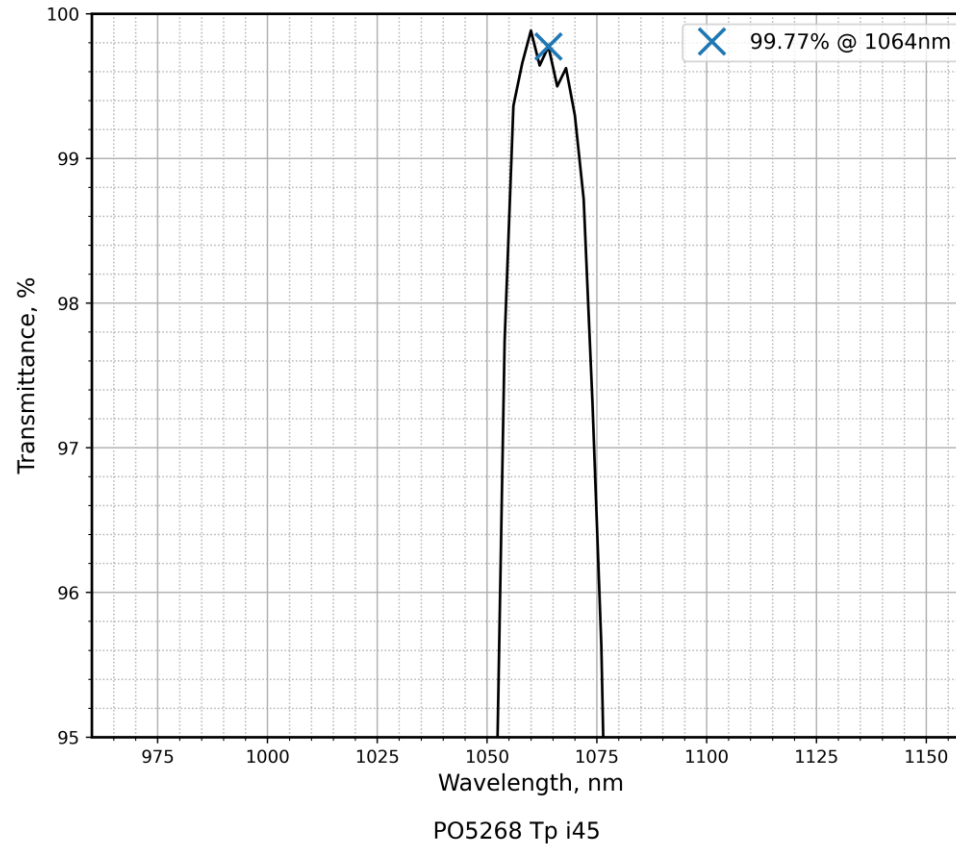


Fig. 2.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRs>99.9%@1064 nm + HTp>98%@1064 nm (Tp/Ts >10001), AOI=45 deg +/-1 deg  
S2: ARp<0.1%@1064 nm, AOI=45 deg

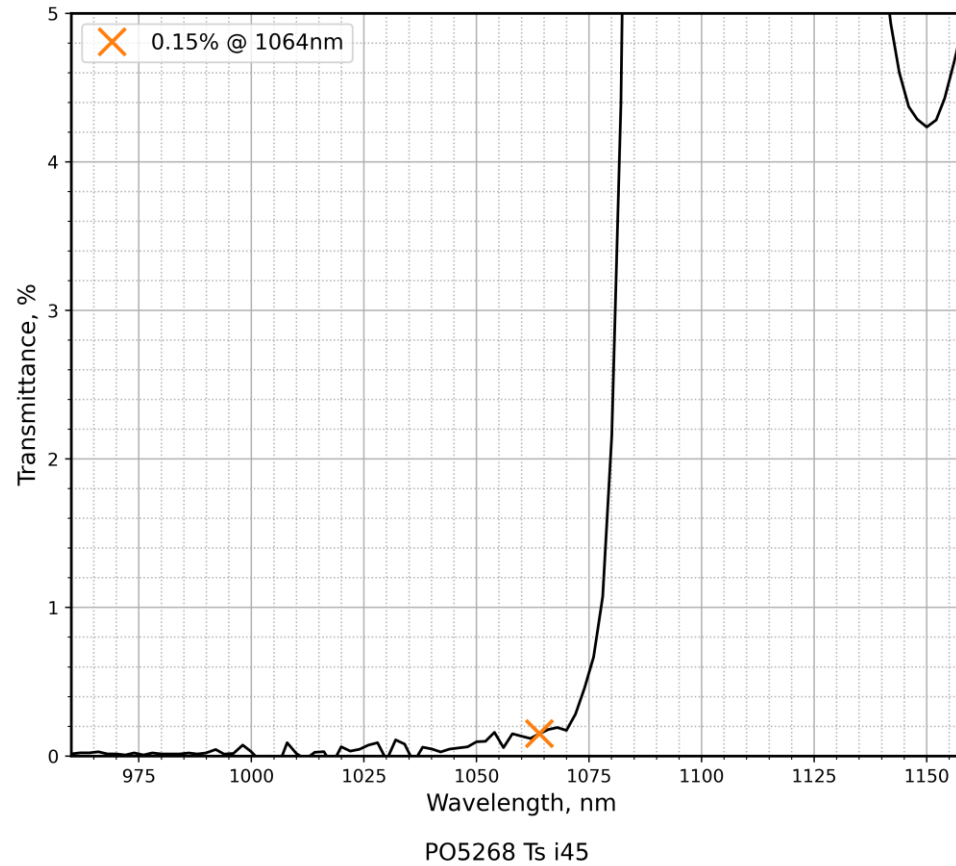


Fig. 3.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRs>99.9%@1064 nm + HTP>98%@1064 nm (Tp/Ts >10001), AOI=45 deg +/-1 deg  
S2: ARp<0.1%@1064 nm, AOI=45 deg

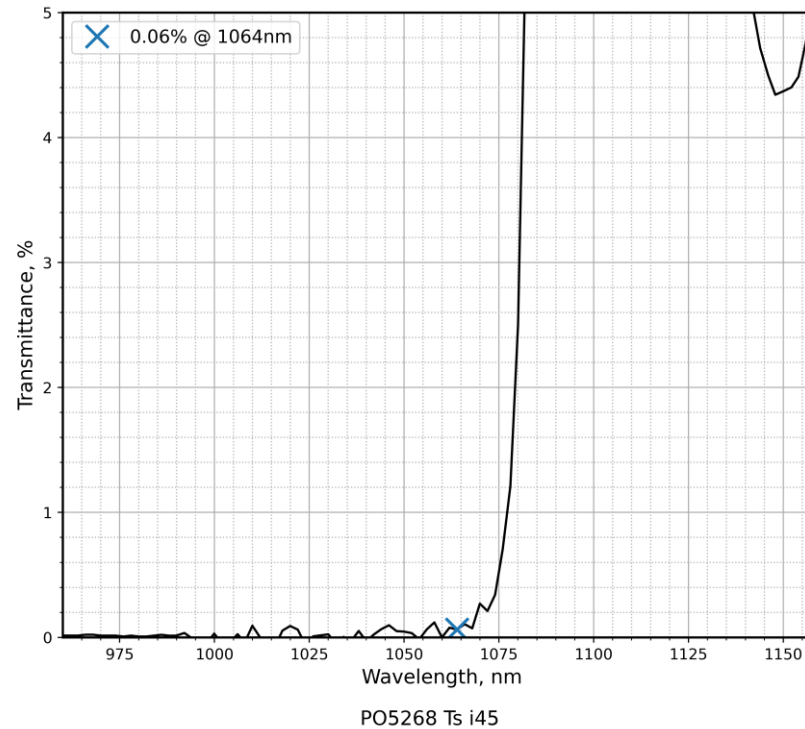


Fig. 4.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%